

Development of the

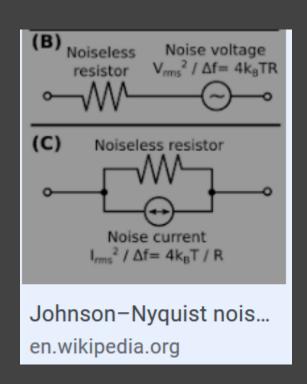
FDM Baseband Feedback

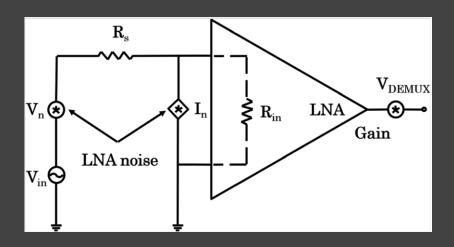
I. FEE Noise Model



Amin Aminaei, 28 September 2020

FEE Model



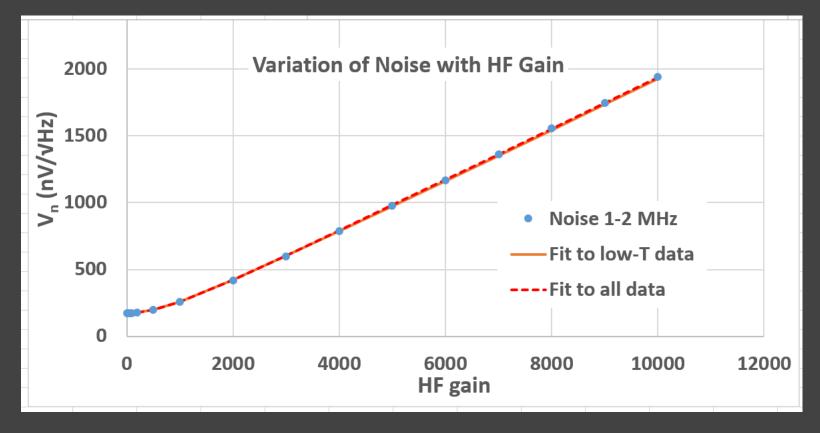


LNA: Vn=315pV/(Hz)^0.5 In=5.4pA/(Hz)^0.5 DEMUX Vn=173nV/(Hz)^0.5 Wang et al., 2020

FEE7 Bandwidth is ~ 38.75 MHz, (Test Procedure FEE-7, SRON report, D. Boersma, 2014) Analysis is initially done in FDM range



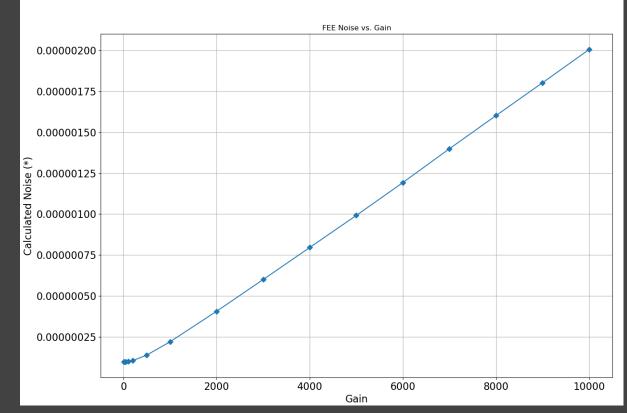
Measured Noise of FEE versus Gain.



Rin = 129 Ohm, Rs = 91.6 Ohm, T=1.3 K to 4K



T=1.3K-3.5K Gain=10,100,1000,10000 (Test Points for LT-Spice) $R_{in}=129 Ohm$ $R_{s}=91.6 Ohm$ In=5.4pA/rt.(Hz) Vn=315pV/rt.(Hz) $V_{n.Demux}=173nV/rt.(Hz)$ $k_{B}=Boltzmann constant$ (1.38e-23)



If
$$R_{lead} \sim 0$$

 $V_{Model}^2 = V_{n.Demux}^2 + Gain^2 (I_n^2, R_s^2 + V_n^2 + 4.k_B \cdot T.R_s) \cdot (R_{in}/(R_{in} + R_s))^2$
 $V_{Model}^2 = V_{n.Demux}^2 \cdot (Noise DEMUX) + Gain^2 (I_n^2, R_s^2) \cdot (R_{in}/(R_{in} + R_s))^2) \cdot (FEE Current Noise) + Gain^2 (V_n^2) \cdot (R_{in}/(R_{in} + R_s))^2) \cdot (FEE Voltage Noise) + Gain^2 (4.k_B \cdot T.R_s) \cdot (R_{in}/(R_{in} + R_s))^2 \cdot (R_s Noise)$



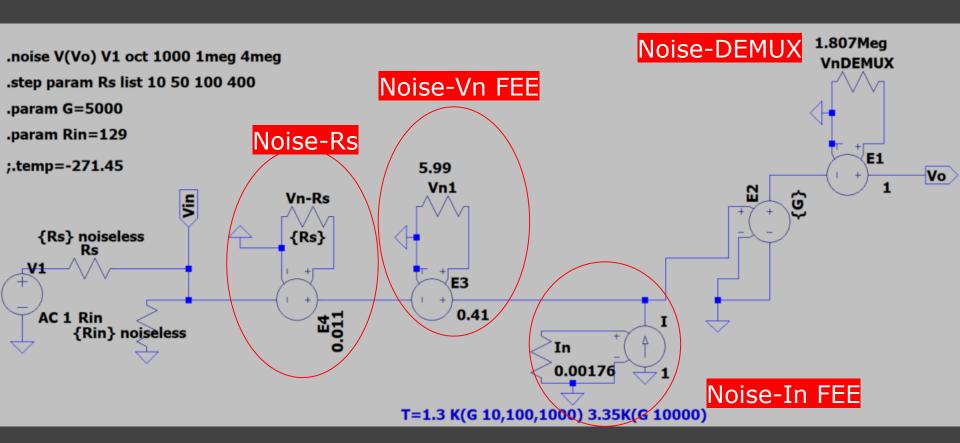
Noise vs. Rin, Rs FEE which has 74-dB gain (5000) in the range 1-5 MHz and active input impedance

1/19/2020 e.Proofing At 1.3 K, the output noise as a function of R_s with different R_{in} . The fitted current noise is $5.4 \pm 0.1 \, \mathrm{pA} / \sqrt{\mathrm{Hz}}$, while the fitted voltage noise $315 \pm 10 \text{ pV}/\sqrt{\text{Hz}}$, both identical to the fitted parameters at 50 mK. (Color figure online) 1400 Fitted line Voltage noise [nV/√Hz] R_{in} 40 Ω ${f R}_{
m in}$ 50 Ω 1200 * R_{in} 70 Ω • R_{in} 88 Ω \circ R_{in} 109 Ω 1000 • R_{in} 129 Ω 800 600 400 50 100 150 200 250 300 350 400 Source resistance R_{ϵ} [Ω]

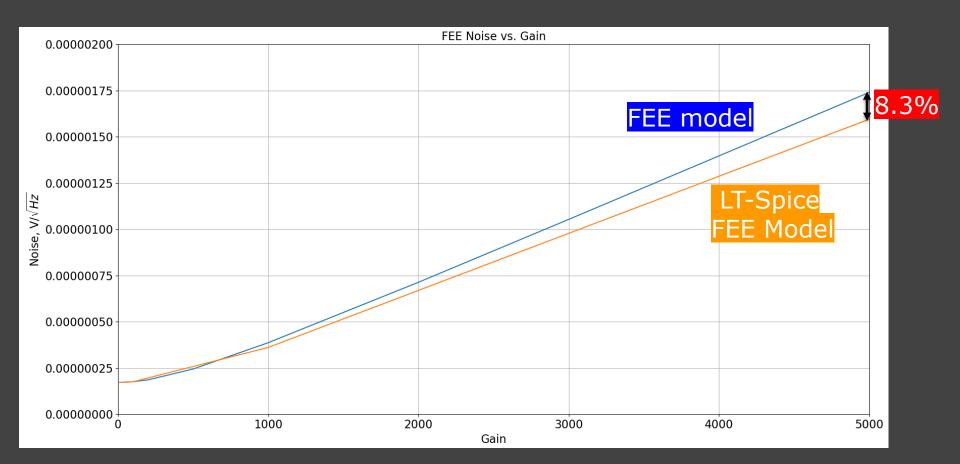
The best fits in Fig. 5 illustrate the identical (within the uncertainty) current noise and the voltage noise of the LNA as what we found from 50 mK data, confirming the model. Thus, we have now derived the noise data of our LNA.

https://eproofing.springer.com/journals_v2/printpage.php?token=CssLS3GuPVYKfvASBawBLg_AVJE3p83Hnc9GM-300

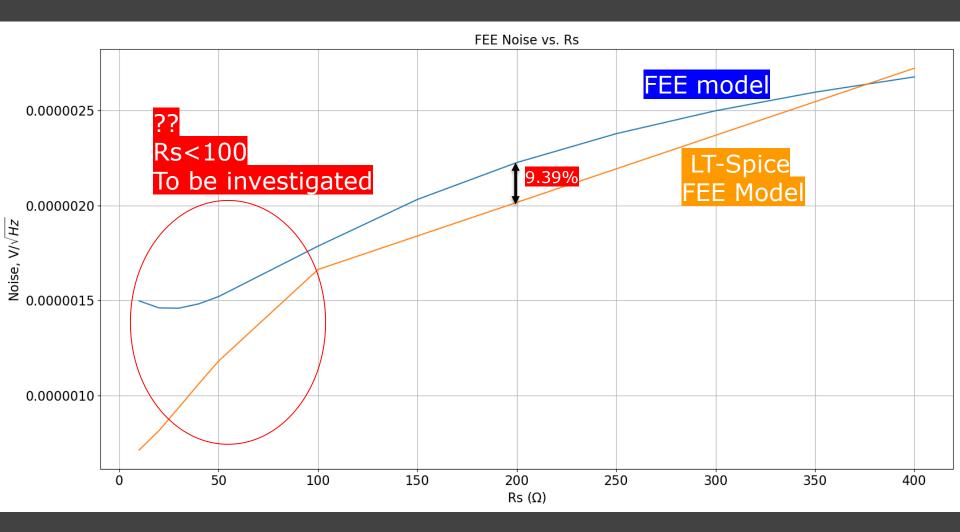
LT-Spice Model



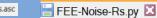


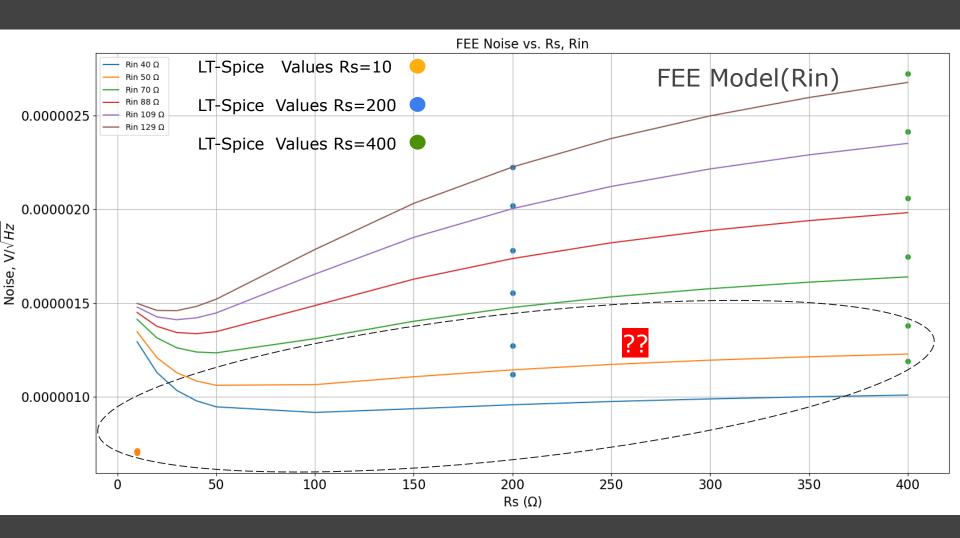




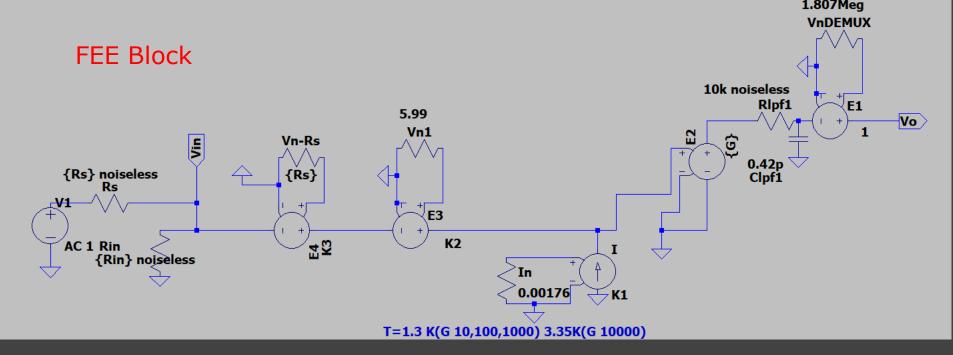










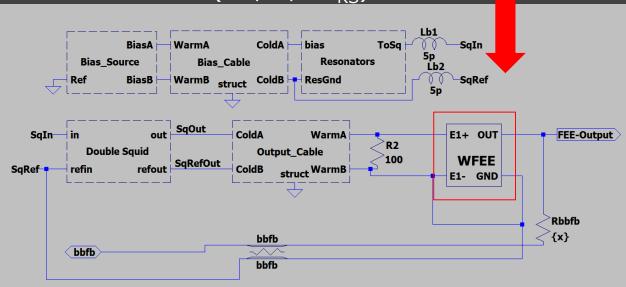


The LTSpice FEE Transformed Noise values (Vn,In, Vn_{RS}) is extracted from the

Noise Model written in Python to match the measurement.

FEE block also includes Vndemux, Gain, Bandwidth, Rs, Rin. To be used for FDM BBFB.





Backup Slides



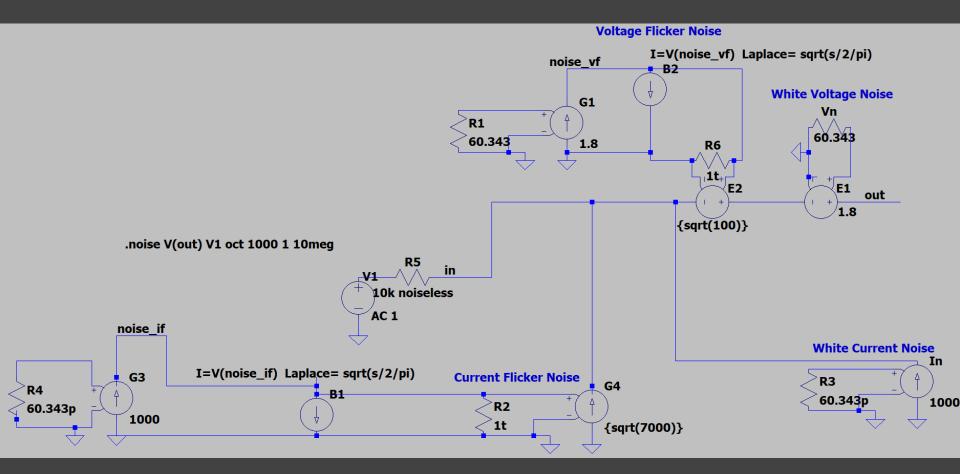
$\mathbf{R}_{\mathsf{Lead}}$

```
V_{\text{measured}}^2 = V_{\text{Demux}}^2 + \text{Gain}^2 (I_n^2. R_s^2 + V_n^2 + 4.k_B . T.(R_s - R_{\text{lead}})_+ 4.k_B . T_{\text{lead}}. R_{\text{lead}})_+ (R_{\text{in}}/(R_{\text{in}} + R_s))^2)
Rlead=0.5 \ Ohm
Tlead=100K
```

```
If R_{lead} \sim 0 (Test points) V_{measured}^2 = V_{Demux}^2 + Gain^2 (I_n^2. R_s^2 + V_n^2 + 4.k_B . T.R_s). (R_{in}/(R_{in} + R_s))^2) T=1.3K, Gain=5000, R_{in}=88, R_s=10-400 Ohm In=5.4pA/root(Hz) V_{n=315pV/root(Hz)} = 173nV/root(Hz) V_{demux}=173nV/root(Hz) V_{demux}=10-400 Negative V_{demux}=173nV/root(Hz) V_{demux}=173nV/root(Hz) V_{demux}=173nV/root(Hz)
```



Flicker Noise, Thermal Noise Simulation for a commercial Amplifier

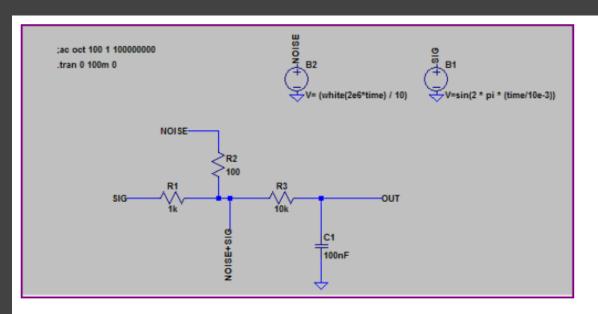


OPA838 input noise model

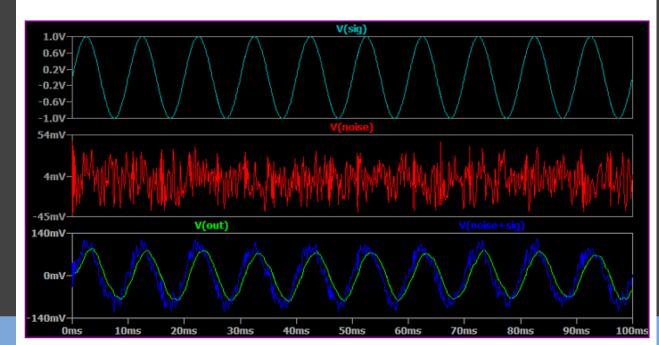
Reproduced from [2]



Transient Noise Analysis LT-Spice



Simulation:



SRON

After [3]

References:

[1]Wang et al., 2020

[2]

https://axotron.se/blog/voltage-and-current-noise-sources-inltspice-noise-simulations/

- [3] https://electronics.stackexchange.com/questions/55233/how-do-you-simulate-voltage-noise-with-ltspice
- [4]
 https://www.allaboutcircuits.com/technical-articles/how-to-perform-transient-analysis-noise-simulation-LTspice/